

Notice of References Cited	Application/Control No. 10/588,292		Applicant(s)/Patent Under Reexamination YABE ET AL.	
	Examiner C. Melissa Koslow		Art Unit 1793	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,641,933	11-2003	Yamazaki et al.	428/690
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